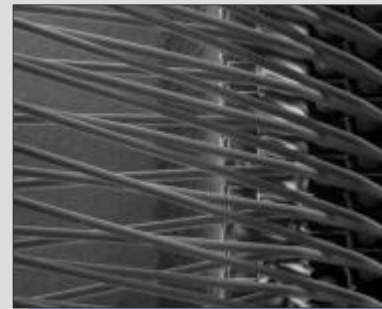
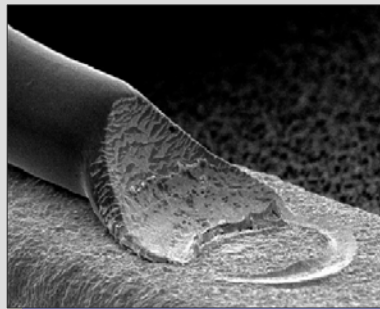
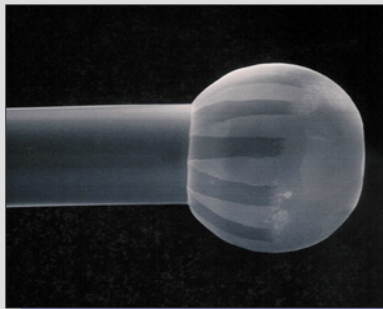


Microbonds X-Wire™ Technology Overview



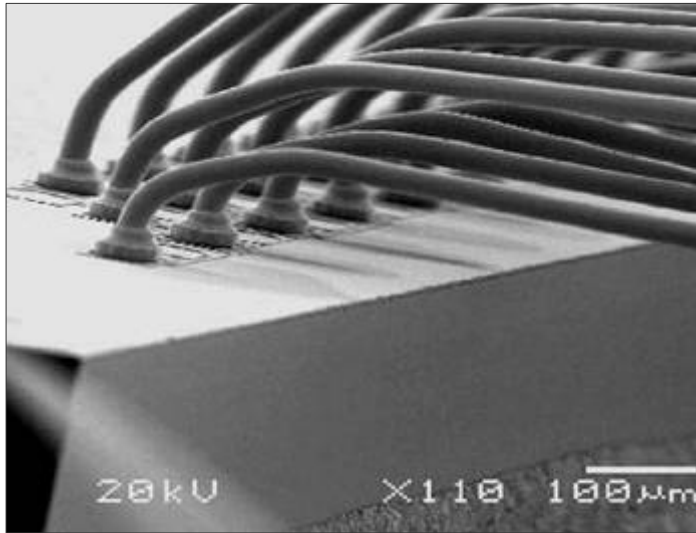
X-Wire™ Technology

- ✓ Enables Cost Effective Solutions to Today's Packaging Challenges
- ✓ Leverages Current Wire Bonding Knowledge, Infrastructure and Supply Chain
- ✓ Extends Ability of Wire Bonding to Address Geometry, Density and Yield Requirements
- ✓ Flexible, Proven Technology that Uses Tanaka's Industry Leading Bond Wires

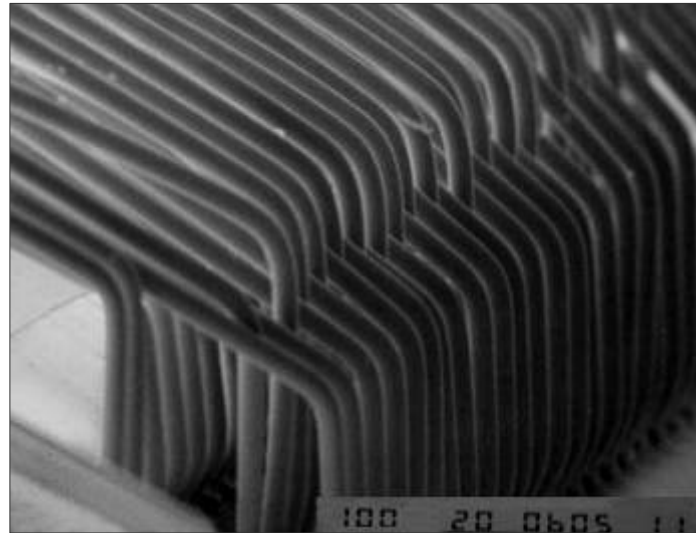
Microbond's X-Wire™ Technology Insulated Wire Bonding

- ✓ Removes Limitations to Current Wire Bonding Design Rules
- ✓ X-Wire™ Technology Allows:
 - ▶ Crossing Wires
 - ▶ Touching Wires
 - ▶ Long Wires
 - ▶ Wire Sweep
 - ▶ Corner Wires

Bare Wire Vs X-Wire™

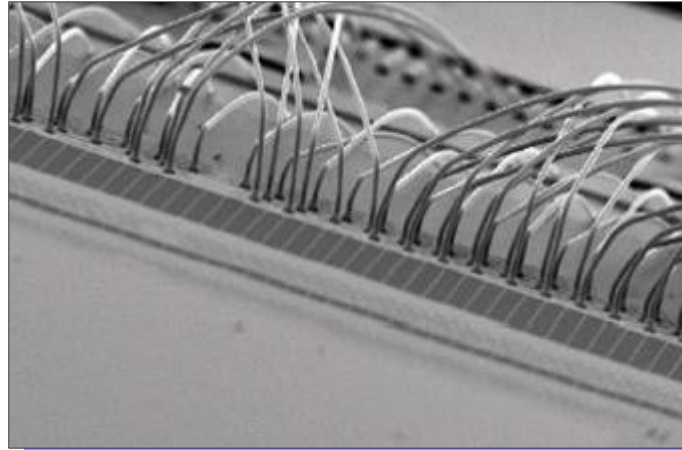
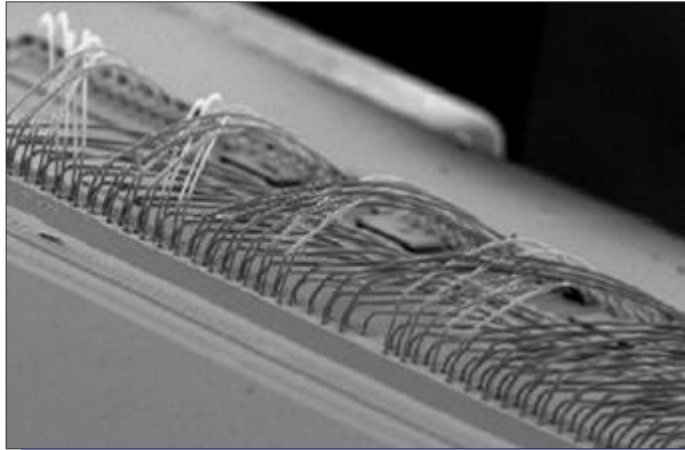


Bare Wire



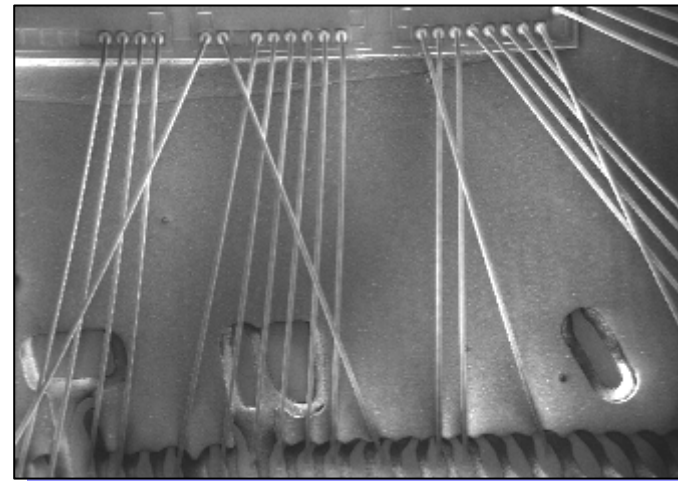
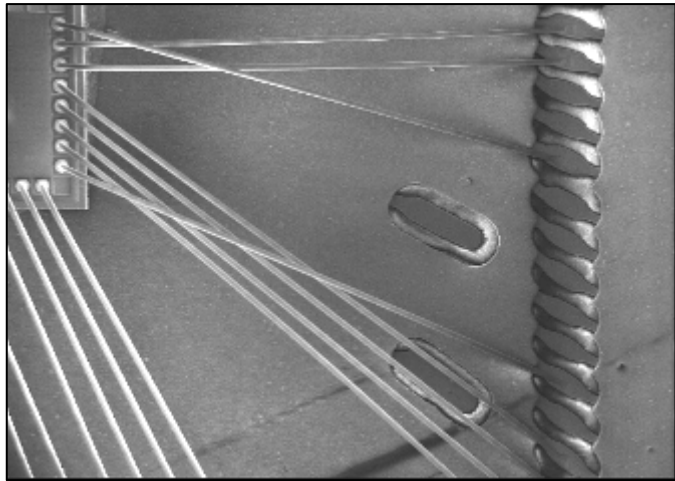
X-Wire™

X-Wires™ - Broadens Wire Bonding Rules



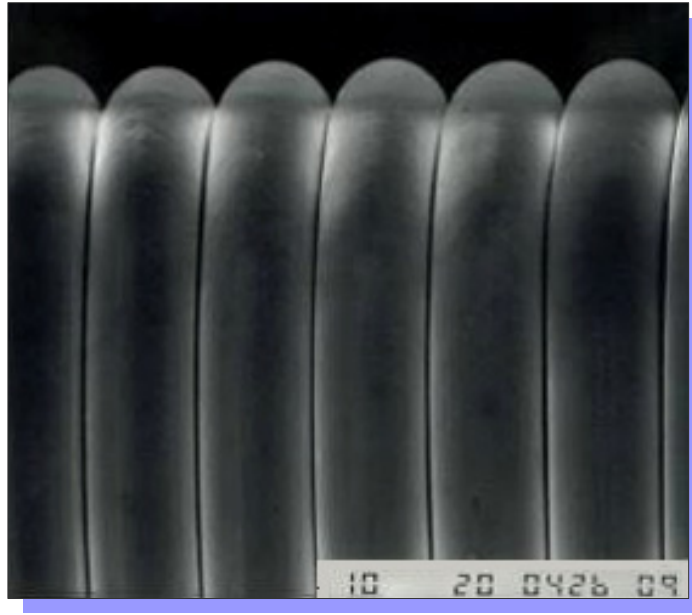
- Actual Test Vehicle Used in Reliability Testing
- Over 500 Crossed Wires per Package

X-Wires™ - Long Wires Can Cross & Touch



- Long Wires Crossing & Touching
- Long Corner Wires Crossing & Touching

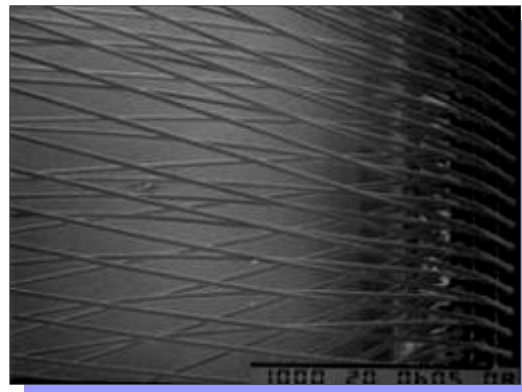
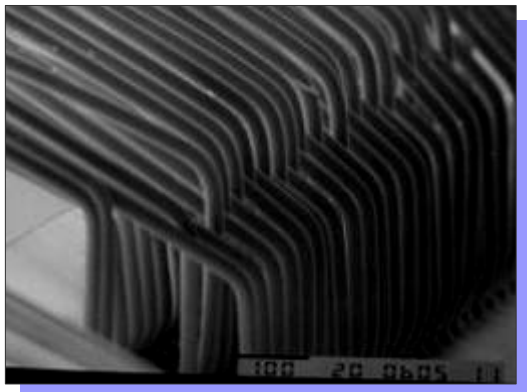
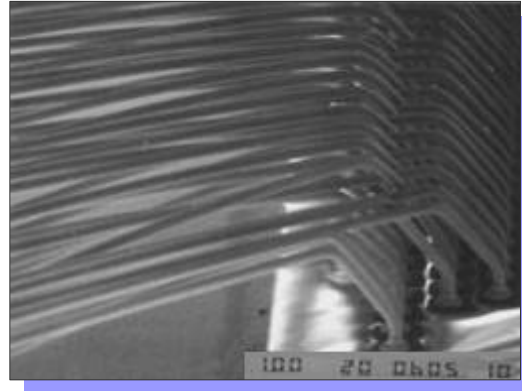
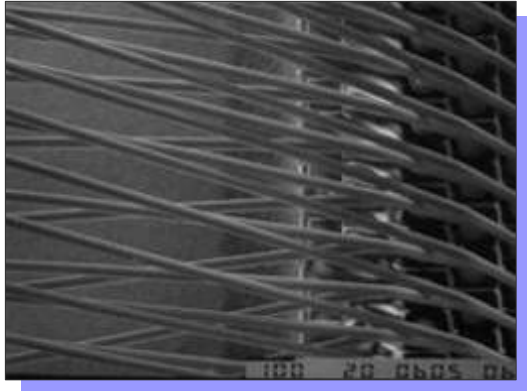
X-Wire™ Simplifies Wire Looping



- X-Wire™ Insulation Coating Features
 - ▶ Excellent Adhesion and Flexibility
 - ▶ No Cracking or Flaking

X-Wire™ Enables Advanced Packages

X-Wire™



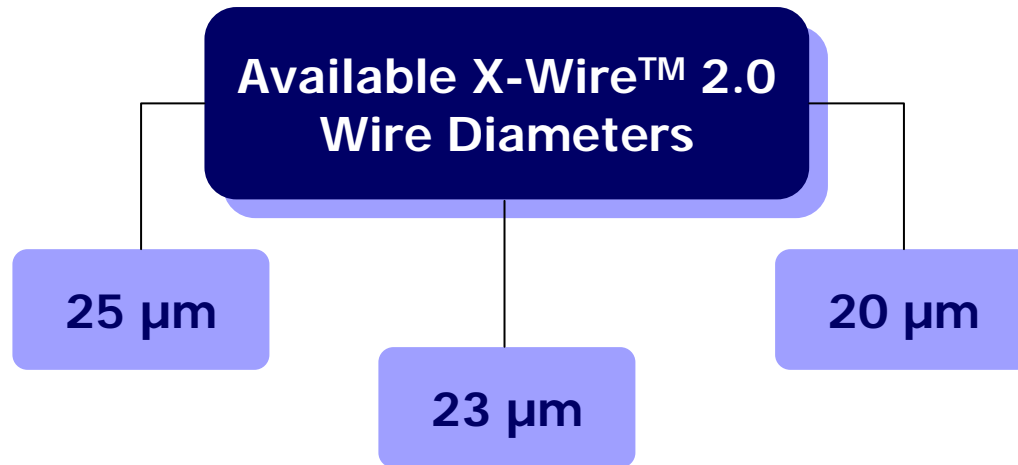
X-Wire™ Benefits

X-Wire™



X-Wire™ Benefits

X-Wire™



Wire Diameter	25 μm	23 μm	20 μm
Pitch Capability	60 μm	50 μm	45 μm
Wire Bonder Platform	ASM Eagle / K&S Maxum		

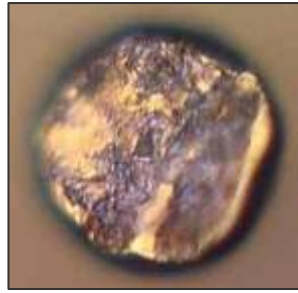
X-Wire™ IMC Data



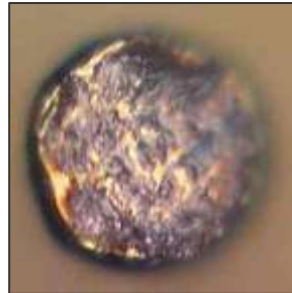
IMC of X-Wire™ at 0 hrs



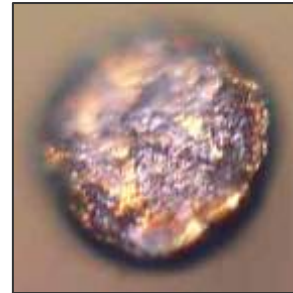
> 85 %



> 75 %



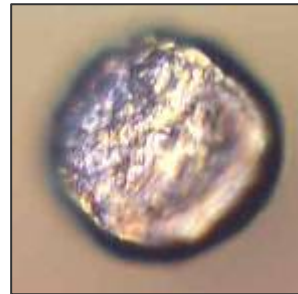
> 95 %



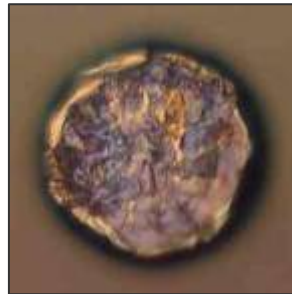
> 85 %



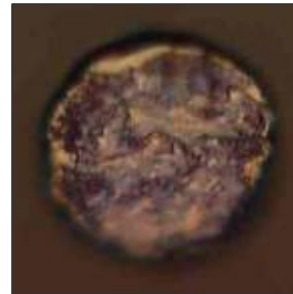
> 80 %



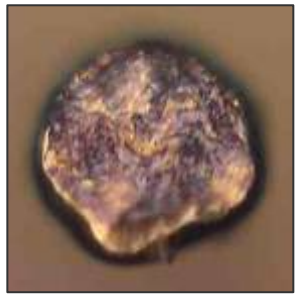
> 85 %



> 90 %



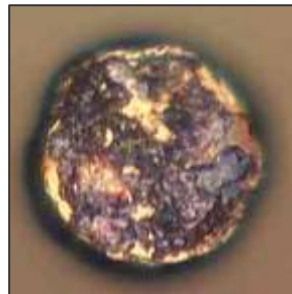
> 90 %



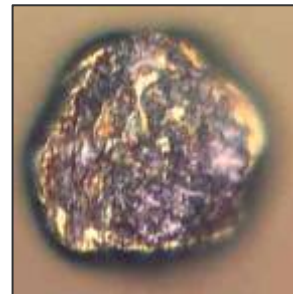
> 90 %



> 80 %



> 80 %



> 90 %

IMC of X-Wire™ After Aging

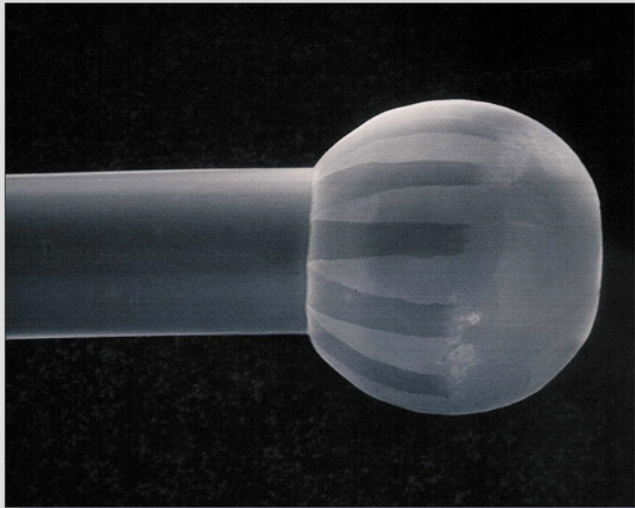
After Baking Test at 175°C		
0 hr	96 hrs	192 hrs



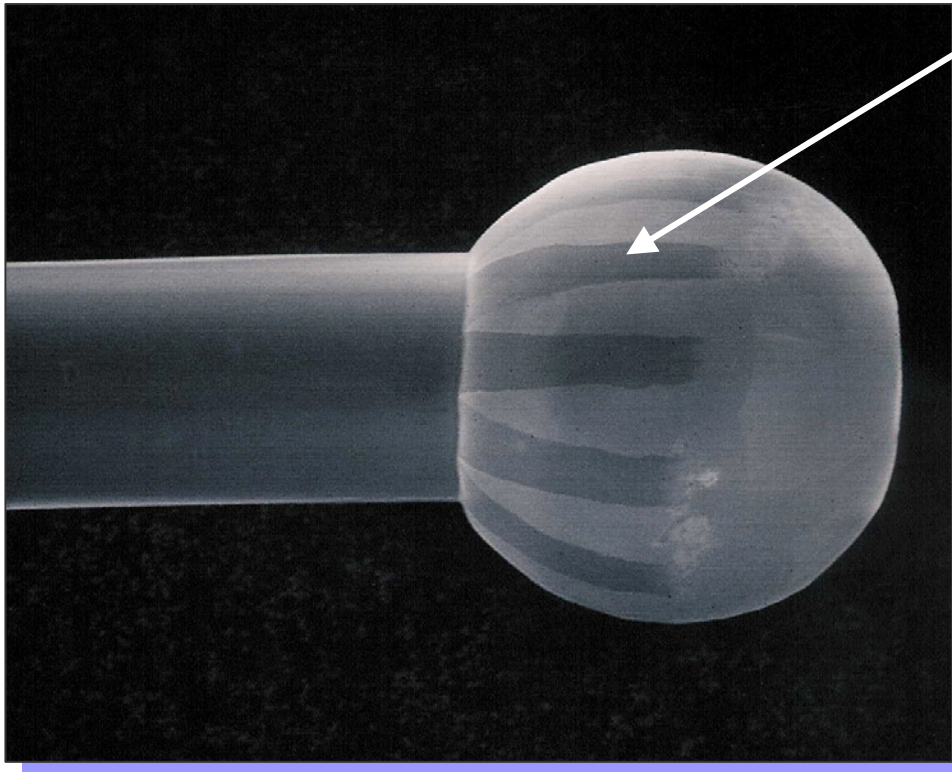
IMC Summary

- ✓ Greater than 70 % IMC Coverage
- ✓ Intermetallic Forms Easily *Through Coating* on Bonded Ball
- ✓ Passed 0 hr, 96 hrs & 192 hrs Aging Test at 175°C

X-Wire™ Ball Bond Data



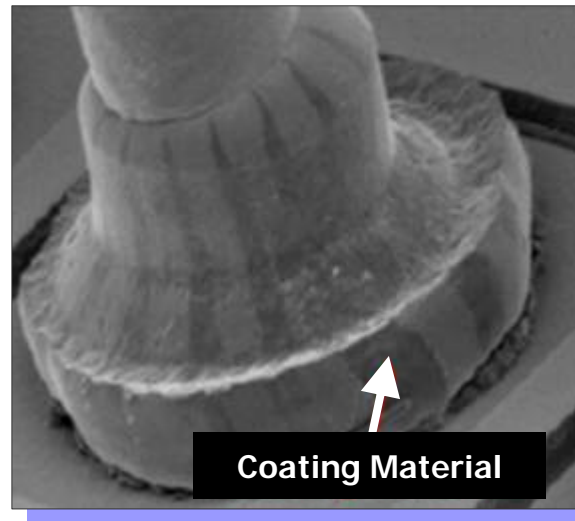
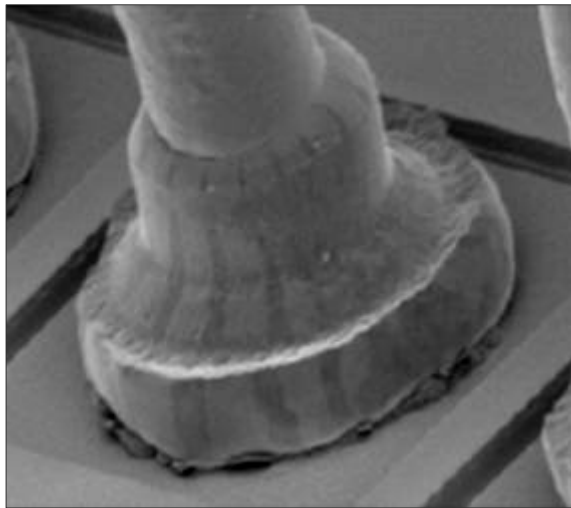
X-Wire™ Free Air Ball



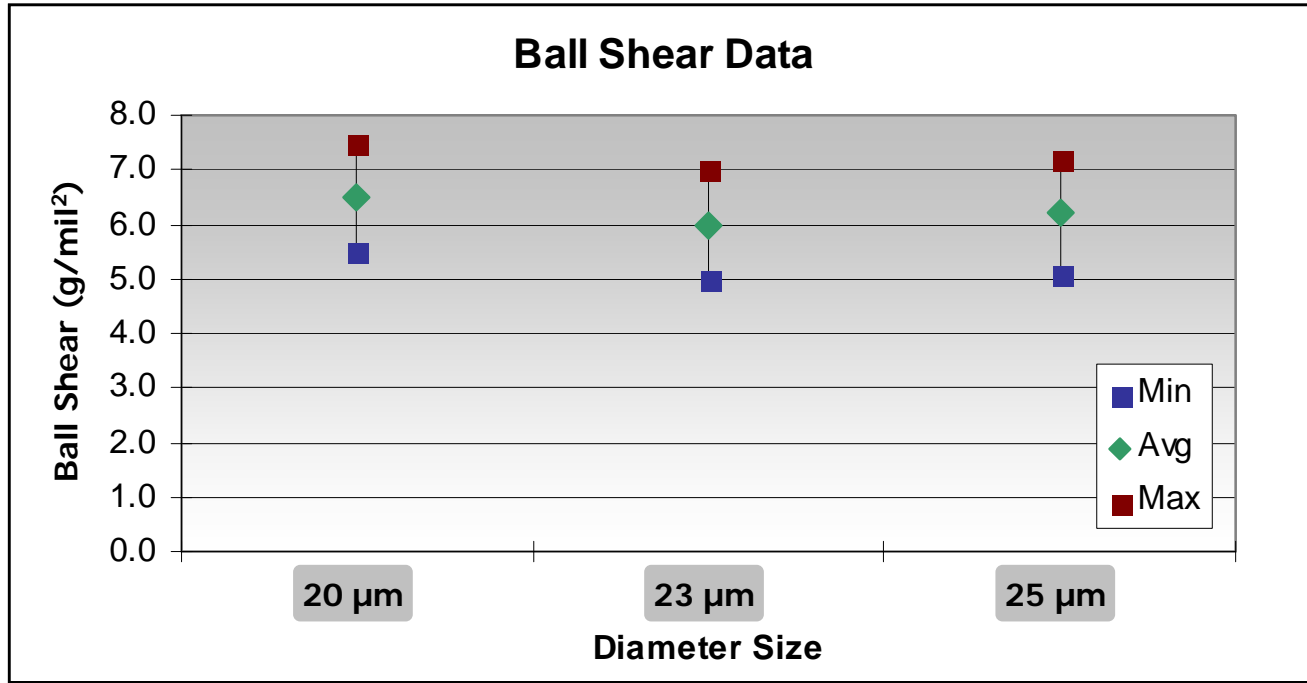
- ✓ Stripes Indicate Coating Presence
- ✓ Wire is Fully Coated Right Down to Neck
- ✓ No Melting of Coating Material

X-Wire™ Bonded Ball

- ✓ Presence of Coating on the Ball Bond

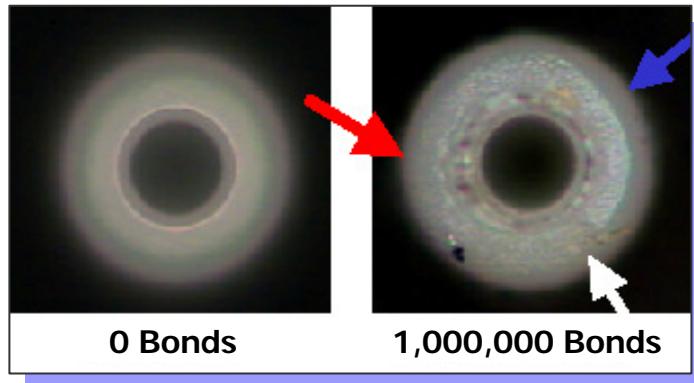


X-Wire™ Ball Shear Data



X-Wire™ - No Capillary Build Up

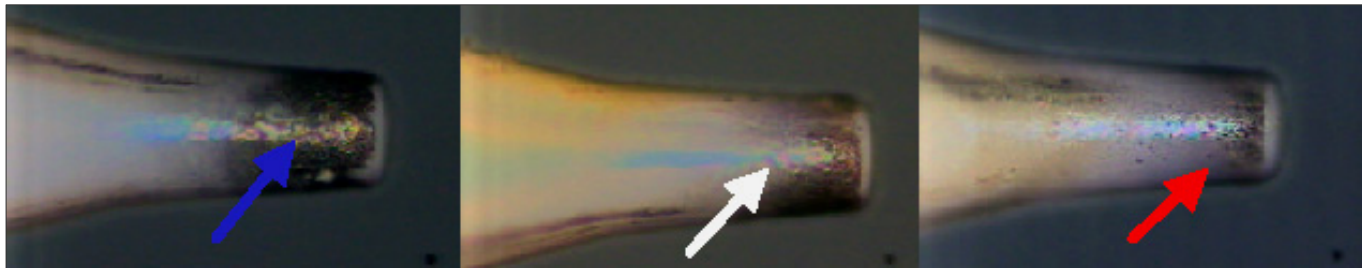
Capillary Inspected After



Negligible Build Up in Capillary Wall Observed



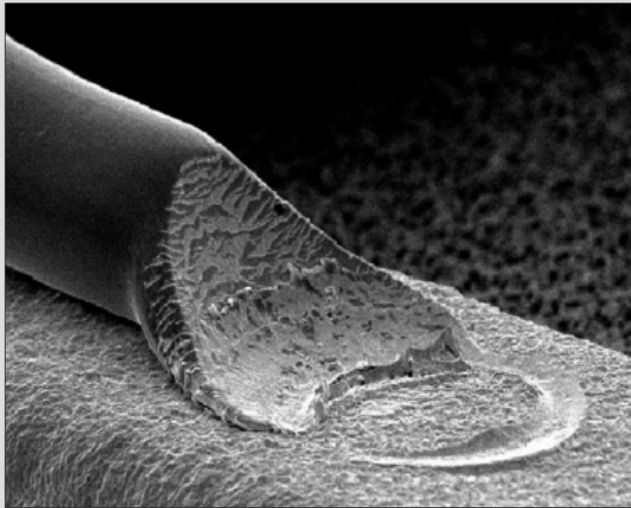
Side View of the 1,000,000 Bonds. Capillary Viewed from Different Angles



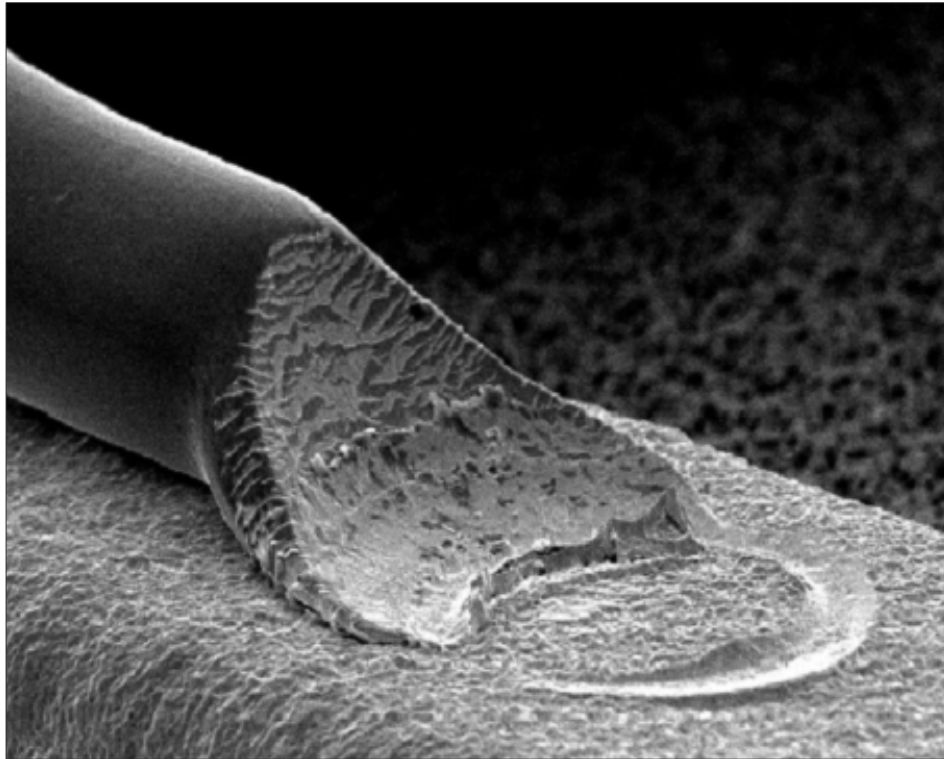
X-Wire™ Ball Bond Summary

- ✓ Small Ball Pitch Capability
- ✓ High Ball Shear Strength
 - ▶ Comparable to Bare Wire
- ✓ Long Capillary Life

X-Wire™ Stitch Bond Data

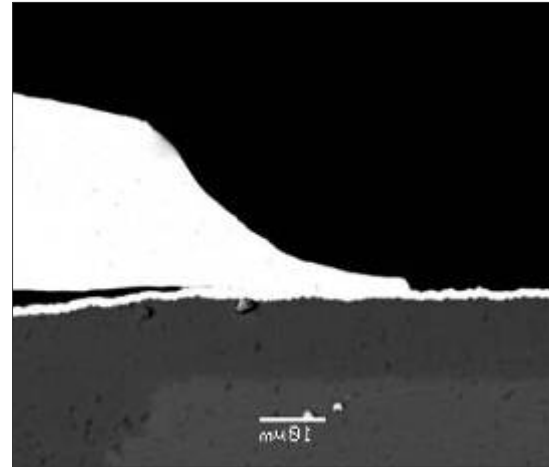
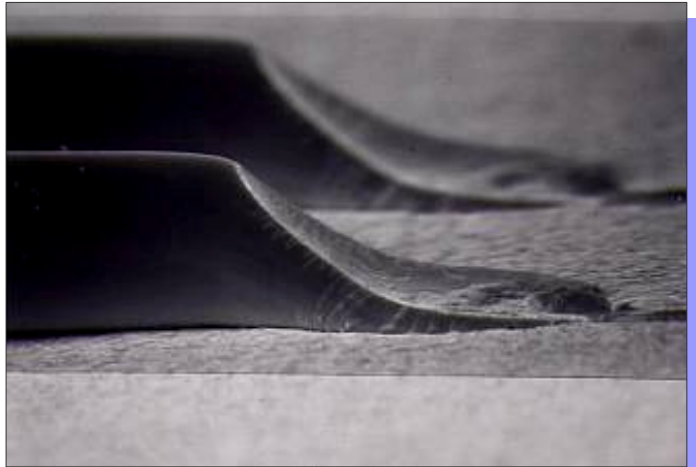


X-Wire™ Stitch Bond

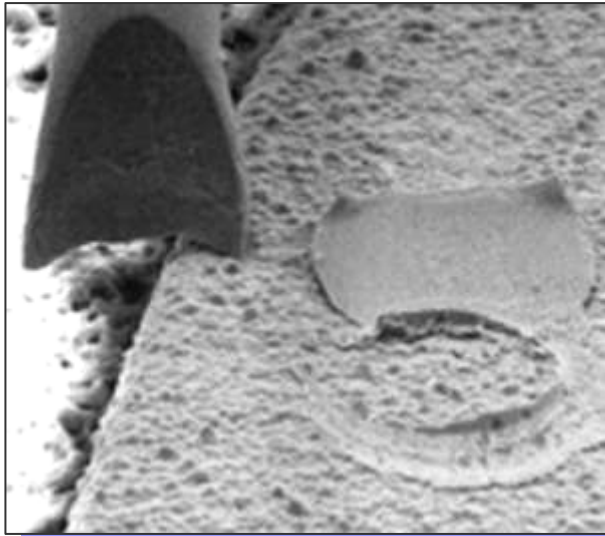


- ✓ Bond Through Coating
- ✓ Use Standard Wire Bonder
- ✓ Use Standard Capillary
- ✓ Good Pull Strength
- ✓ Laminate Substrate
- ✓ Leadframe Substrate

X-Wire™ Stitch Bond Standard Forward Bonding



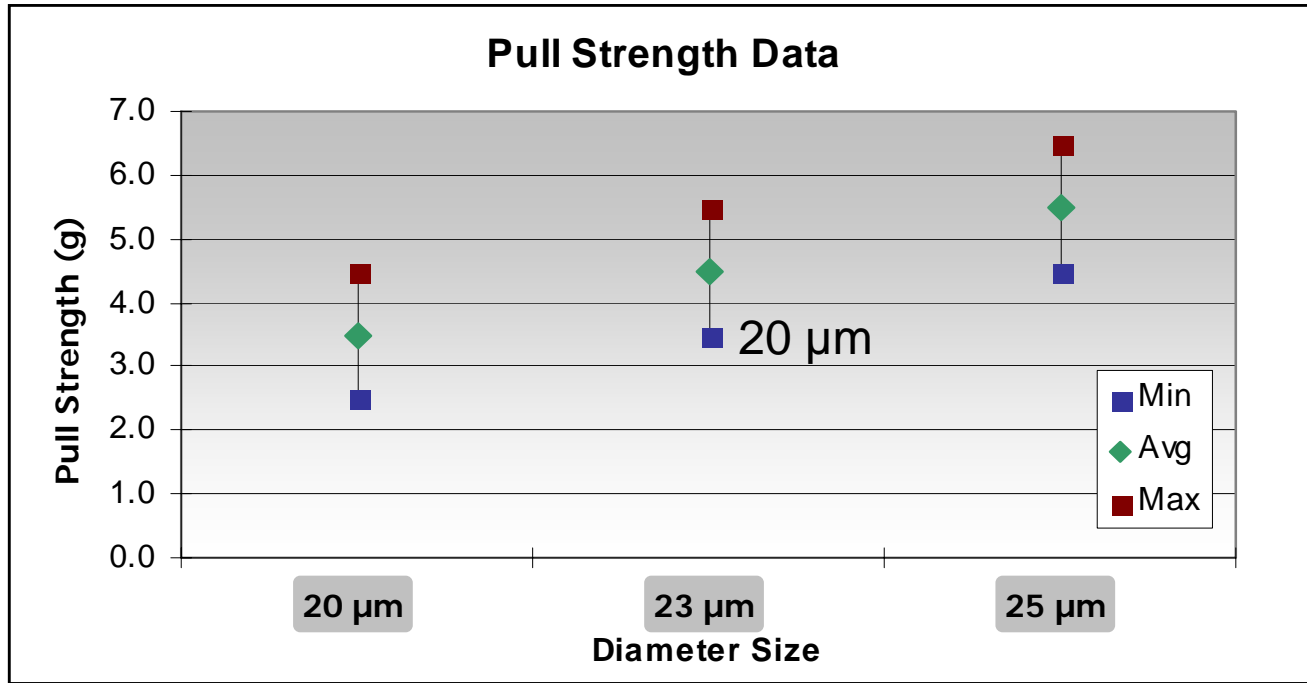
X-Wire™ Stitch Bond Remaining After Stitch Pull



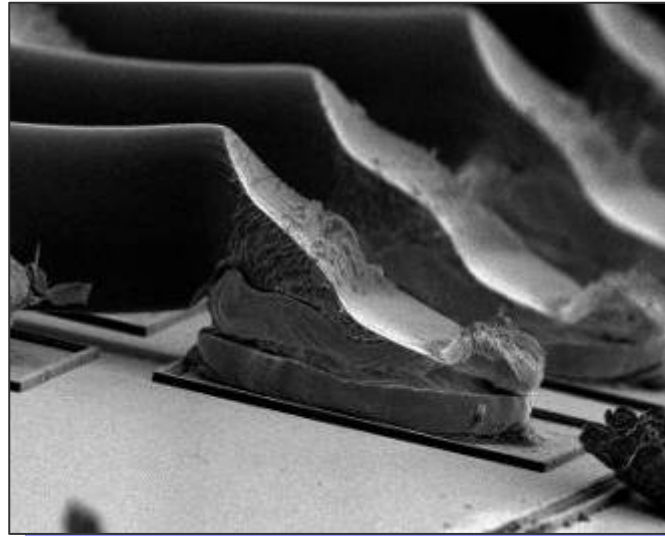
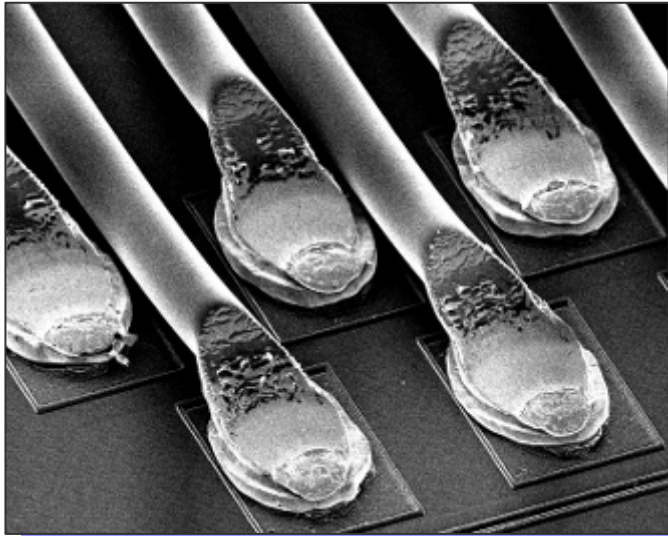
Source: ASM Pacific Technology Ltd.

X-Wire™ Pull Strength Data

X-Wire™



X-Wire™ Reverse Stand-Off Stitch Bonding



Stitch Bond Summary

- ✓ Bond Through Coating
- ✓ Good Pull Strength
- ✓ Laminate & Leadframe Capability
- ✓ Reverse Stitch Bonding (RSSB) Capability

X-Wire™ Evaluation by ASM Pacific using Eagle 60 Wirebonder



The Process of Innovation™

	X-Wire™ (20 μm)	X-Wire™ (25 μm)
1st Bond Geometry		
Bond Pad Pitch	50	65
Ball Diameter (μm)	39	53
Ball Height (μm)	10	12
1st Bond Strengths		
Shear Force (g)	12.0	23.2
Shear Strength (g/mil²)	6.5	6.9
2nd Bond Strengths		
Stitch Pull (g)	4.4	8.5

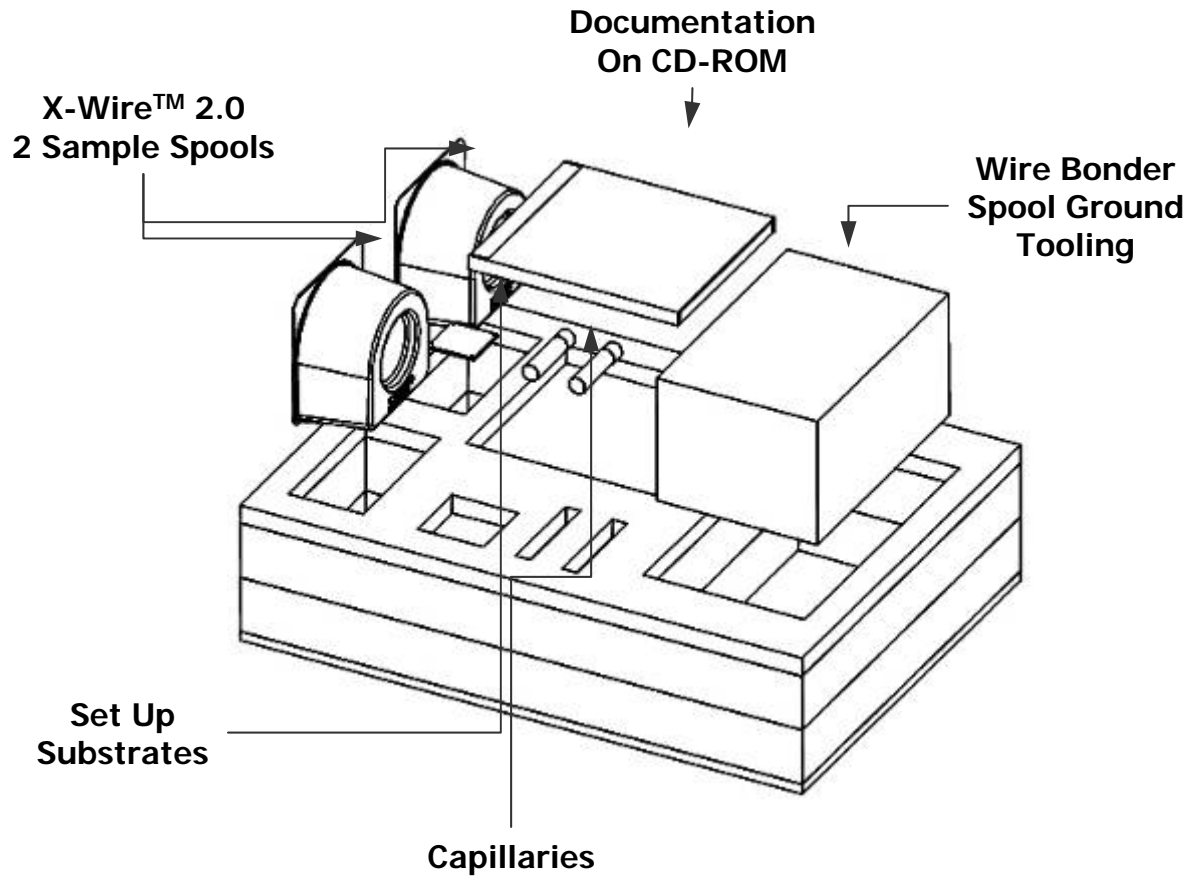
X-Wire™ Reliability Data

REL Data Summary

- ✓ **MSL Level 3: Pre-Conditioning**
 - ▶ Condition: 30°C, 85 % RH, 192 hrs
- ✓ **Biased HAST**
 - ▶ Condition: 130°C, 85 % RH, 4 V, 100 hrs
- ✓ **High Temperature Storage**
 - ▶ Condition: 150°C, 1000 hrs
- ✓ **Thermal Cycling**
 - ▶ Condition: -55°C to 125°C, 1000 cycles

X-Wire™ 2.0 Head Start Kit

X-Wire™ 2.0 Head Start Kit Content

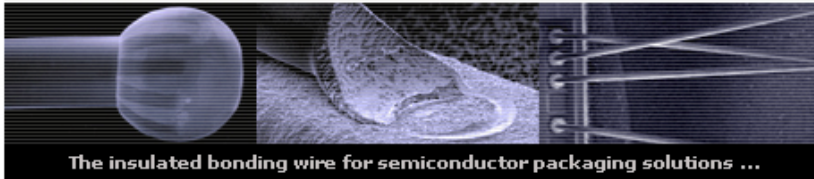


X-Wire™ 2.0 Head Start Kit Features

- ✓ Allows Customer to Perform Internal Feasibility & Bondability Testing
- ✓ Includes Materials on Current Best Known Methods and Recommendations for Process Setup & Optimization
- ✓ ASM and K&S Bonder Platforms Supported
- ✓ Includes Choice of Wire Diameters
 - ▶ 25 µm, 23 µm, 20 µm Diameter X-Wires™ 2.0







Microbonds

X-Wire™ 2.0






Welcome
To X-Wire™ 2.0
Head Start Kit
Technical Documentation


CHAPTER 1

-  [1.1 X-Wire\(TM\) 2.0 Product Bulletin - Overview & Roadmap](#)
-  [1.2 X-Wire\(TM\) 2.0 Technical Data Sheet](#)
-  [1.3 X-Wire\(TM\) 2.0 Handling & Storage Requirements](#)
- [1.4 Required Wire Bonder Modification Procedures](#)
 -  [1.4.1 ASM Wire Bonder Modification Procedure](#)
 -  [1.4.2 K&S Wire Bonder Modification Procedure](#)
-  [1.5 Wire Clamp Pads Replacement Instructions](#)


CHAPTER 2

-  [2.1 Capillary Selection Guidelines for X-Wire\(TM\) 2.0](#)
- [2.2 X-Wire\(TM\) 2.0 Wire Bonding Process Optimization](#)
 -  [2.2.1 ASM Bond Parameters Optimization](#)
 -  [2.2.2 K&S Bond Parameters Optimization](#)

CHAPTER 3

-  [3.1 Design Rules - X-Wire\(TM\) 2.0 Wire Bond Layouts](#)

CHAPTER 4

-  [4.1 Plasma Treatment of X-Wire\(TM\) 2.0 Bonded Device](#)

APPENDIX

-  [Getting Started](#)
-  [Image Gallery](#)
-  [References & Acknowledgments](#)



All Documents in Adobe Acrobat Format (PDF)
["Get Adobe Reader"](#)



[Terms & Conditions](#) | [Copyrights & Trademarks](#) | [Disclaimer](#) | [Contact Us](#)

Copyright © 2006 [Microbonds Inc.](#), All Rights Reserved.

X-Wire™ 2.0 Head Start Kit Availability & Ordering Information

✓ To Order Please Contact

Tanaka Asia

Mr. Frank Tanaka

K-TANAKA@ml.tanaka.co.jp

T: + 81-3-6311-5588

Mr. Takeshi Inaba

T-INABA@ml.tanaka.co.jp

T: + 81-3-6311-5588

Microbonds Inc.

Mr. William (Bud) Crockett

bcrockett@microbonds.com

T: +1 408-504-4971